Power MOSFET

40 V, 3.3 m Ω , 102 A, Single N-Channel

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- LFPAK4 Package, Industry Standard
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	40	V
Gate-to-Source Voltage	9		V_{GS}	±20	V
Continuous Drain		T _C = 25°C	I _D	102	Α
Current R _{θJC} (Notes 1, 3)	Steady	T _C = 100°C		72	
Power Dissipation	State	T _C = 25°C	P_{D}	68	W
R _{θJC} (Note 1)		T _C = 100°C		34	
Continuous Drain		T _A = 25°C	I _D	24	Α
Current R _{θJA} (Notes 1, 2, 3)	Steady	T _A = 100°C		17	
Power Dissipation	State	T _A = 25°C	P_{D}	3.6	W
R _{θJA} (Notes 1, 2)		T _A = 100°C		1.8	
Pulsed Drain Current	$T_A = 25$	°C, t _p = 10 μs	I _{DM}	554	Α
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +175	°C
Source Current (Body Diode)			Is	65	Α
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 7.0 A)			E _{AS}	215	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	2.2	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

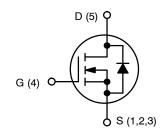
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
40 V	3.3 m Ω @ 10 V	102 A



N-CHANNEL MOSFET



LFPAK4 CASE 760AB



3D5N04C = Specific Device Code A = Assembly Location

WL = Wafer Lot
 Y = Year
 W = Work Week

ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				22		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			10	μΑ
		$V_{DS} = 40 \text{ V}$	T _J = 125°C			100	7
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS}	= 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D$	= 60 μΑ	2.5		3.5	V
Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-7.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 50 A		2.7	3.3	mΩ
Forward Transconductance	9 _{FS}	V _{DS} =15 V, I _D	= 50 A		93		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE					•	•
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 25 V			1600		pF
Output Capacitance	Coss				830		1
Reverse Transfer Capacitance	C _{RSS}				28		1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 20 V; I _D = 50 A			23		nC
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 10 V, V _{DS} = 20	0 V; I _D = 50 A		5.1		1
Gate-to-Source Charge	Q _{GS}				9.0		1
Gate-to-Drain Charge	Q_{GD}				3.5		1
Plateau Voltage	V_{GP}				5.3		V
SWITCHING CHARACTERISTICS (Note &	5)				•	•	•
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 10 \text{ V}, V_{DS}$	s = 20 V,		10		ns
Rise Time	t _r	$I_D = 50 \text{ A}, R_G = 2.5 \Omega$			47		1
Turn-Off Delay Time	t _{d(OFF)}				19		1
Fall Time	t _f				3.0		1
DRAIN-SOURCE DIODE CHARACTERIS	STICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	T _J = 25°C		0.9	1.2	V
		I _S = 50 A	T _J = 125°C		0.78		
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dIS/dt = 100 A/ μ s, I _S = 50 A			37		ns
Charge Time	t _a				18		1
Discharge Time	t _b				19		1
Reverse Recovery Charge	Q _{RR}				23		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

5. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

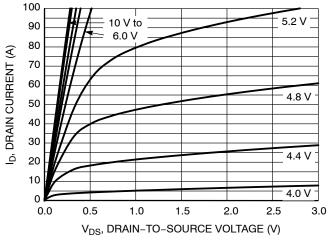


Figure 1. On-Region Characteristics

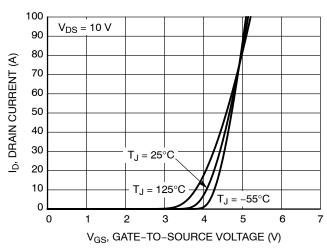


Figure 2. Transfer Characteristics

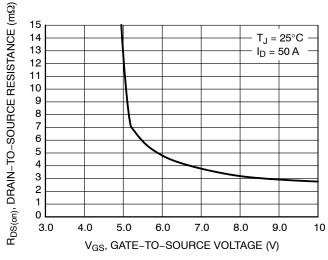


Figure 3. On-Resistance vs. Gate-to-Source Voltage

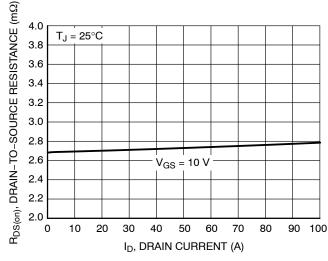


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

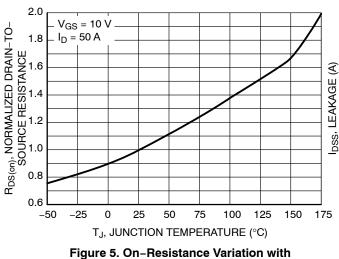


Figure 5. On–Resistance Variation with Temperature

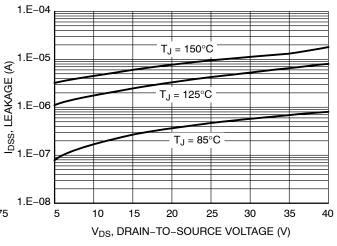


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

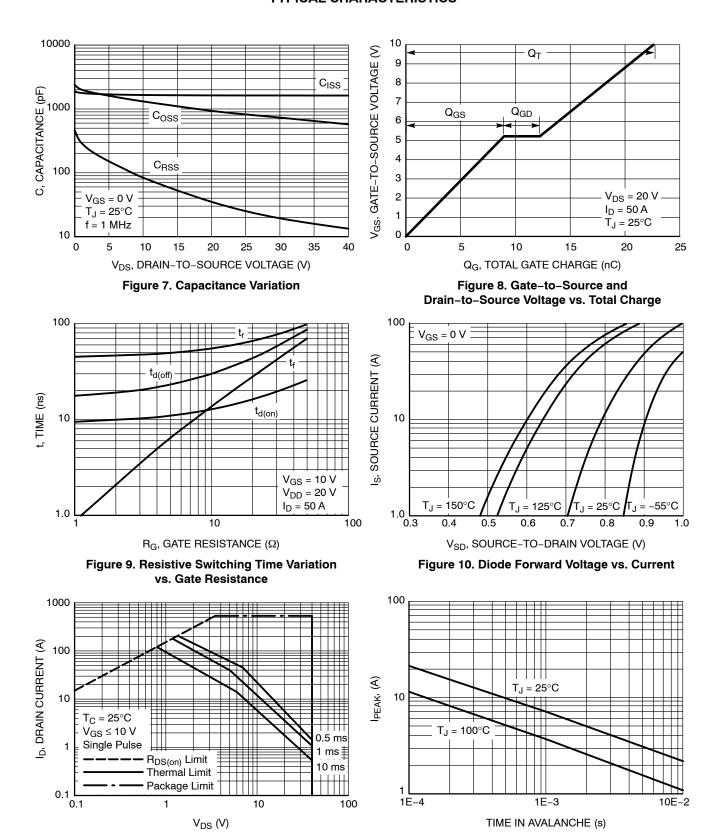


Figure 12. I_{PEAK} vs. Time in Avalanche

Figure 11. Safe Operating Area

TYPICAL CHARACTERISTICS

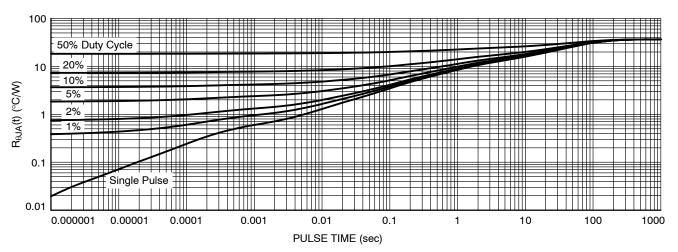


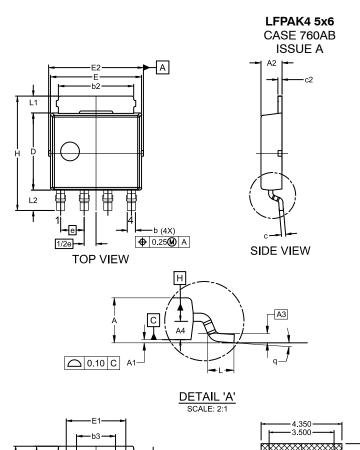
Figure 13. Thermal Characteristics

DEVICE ORDERING INFORMATION

Device	Marking	Package	Shipping [†]
NTMYS3D5N04CTWG	3D5N04C	LFPAK4 (Pb-Free)	3000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

UNIT IN MILLIMETER			
DIM	MIN	NOM	MAX
Α	1.10	1.20	1.30
A1	0.00	0.08	0.15
A2	1.10	1.15	1.20
А3		0.25	
A4	0.45	0.50	0.55
b	0.40	0.45	0.50
b2	3.80	4.10	4.40
b3	2.00	2.10	2.20
b4	0.70	0.80	0.90
O	0.19	0.22	0.25
с2	0.19	0.22	0.25
О	4.05	4.15	4.25
D1	-	-	4.20
D2	3.0	3.10	3.20
D3	0.30	0.40	0.50
Е	4.80	4.90	5.00
ΕΊ	3.10	3.20	3.30
E2	5.00	5.15	5.30
е	1.27 BSC		
Η	6.00	6.15	6.30
L	0.40	0.65	0.85
L1	0.80	0.90	1.00
L2	0.80	1.05	1.30
q	0°	4°	8°

	1.500 1.610 0.700 1.150 1.060 1.150 1.060
BOTTOM VIEW	RECOMMENDED MOUNTING FOOTPRINT

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdt/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor akes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303–675–2176 or 800–344–3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative